	ESC	C	DC	DCUMENT	CHANGE REQUEST				
DCR number	450	Changes re	quired for: Gen	eral	Originator: Steve Thacker (ESCC				
Date: 2008/12	2/08	Date sent: 2	2008/12/08		Organisation: ESA/ESTEC				
Status: IMPLE	Status: IMPLEMENTED								
Title:	Resistor Arrays, F	ixed, Surface M	Iount, Thin Film	, based on Type I	PRA HR				
Number:	4001/025		Issue:	3					
Other documen	ts affected:			•					
Page:									
					Iting from the modification of 4001 issue sed issue 4 Draft B).				
The layout, form	nat and gener								
Paragraph:									
			•	-	Iting from the modification of 4001 issue sed issue 4 Draft B).				
The layout, form	nat and gener								
Original wording	g:								
Proposed wordi	ng:								
	of this Detail Specifi Specification No. 40		•		Specifications, 4001/xxx, for resistors CC format.				
See below for s	ummary of change	s, also see atta	ched proposed	Issue 4 Draft B.					
	ote: known support for active procurement against this specification includes the following Manufacturer: ishay SA Sfernice/France (is willing to support procurement of all variants).								
Summary of ch	anges to the currer	it format, layou	t and content is	as follows:					
-	nd restructure of various sections and paragraphs of the specification, plus other editorial changes based on editorial content of other Detail Specifications already converted to ESCC format.								
2. In the Maxim ESCC2134000)	•	mend "Insulatic	on Voltage" to be	e "Isolation Voltag	ge" (to be consistent with ESCC4001 &				
3. Figure 1 Para	ameter Derating Re	equirements mo	oved to be a note	e to the Maximum	n Ratings table (in para 1.5).				

	SC	C	DOCUMENT	CHANGE REQUEST							
DCR number	450	Changes required for:	General	Originator: Steve Thacker (ESCC							
Date: 2008/12/08		Date sent: 2008/12/08		Organisation: ESA/ESTEC							
Status: IMPLEMEN	TED										
4. New para 2.5 for R	4. New para 2.5 for Resistance to Soldering Heat test is added.										
5. Insulation Resistan	ce test is adde	d to Table 2 but is guara	inteed but not tested d	luring screening (in para 2.6.1).							
	-	•		ng to be a fixed sample of 5 mounted eric 4001 issue 2)(in para 2.6.2).							
7. Table 4 is deleted.											
8. Figures 5(a) & 5(b)	are deleted.										
9. Table 6. Amend in Values")	each test the li	mit for initial measureme	ent of Relative Toleran	ce to be " See Para. 2.6.1" (was "Record							
10. Table 6, Delete dr ESCC 4001)(in para 2		re I" reference from Sold	erability & Resistance	to Soldering Heat (to be consistent with							
Justification:											
(see also change deta	ails for each ite	m above):									
format and presentati	on to be consis	•	er ESCC Detail Speci	format. Amendments are made to the fications, already converted to ESCC r DCR409).							
Attachments:											
4001025.pdf, null											
Modifications:											
N/A											
Approval signature:											
Albsutes											
Date signed:											
2008-12-08											



Pages 1 to 16

RESISTOR ARRAY, FIXED, SURFACE MOUNT, THIN FILM

BASED ON TYPE PRA HR

ESCC Detail Specification No. 4001/025

Issue 4 Draft B	November 2008



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DOCUMENTATION CHANGE NOTICE

(Refer to https://escies.org for ESCC DCR content)

DCR No.	CHANGE DESCRIPTION
	Specification updated to incorporate editorial and technical changes per DCR.



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1. <u>GENERAL</u>

1.1 <u>SCOPE</u>

This specification details the ratings, physical and electrical characteristics and test and inspection data for the component type variants and/or the range of components specified below. It supplements the requirements of, and shall be read in conjunction with, the ESCC Generic Specification listed under Applicable Documents.

1.2 <u>APPLICABLE DOCUMENTS</u>

The following documents form part of this specification and shall be read in conjunction with it:

(a) ESCC Generic Specification No. 4001.

1.3 <u>TERMS, DEFINITIONS, ABBREVIATIONS, SYMBOLS AND UNITS</u> For the purpose of this specification, the terms, definitions, abbreviations, symbols and units specified in ESCC Basic Specification No. 21300 shall apply.

1.4 THE ESCC COMPONENT NUMBER AND COMPONENT TYPE VARIANTS

1.4.1 <u>The ESCC Component Number</u>

The ESCC Component Number shall be constituted as follows:

Example: 4001025011001FW1 or 4001025221229FW1

- Detail Specification Reference: 4001025
- Component Type Variant Number: 01 or 22 (as required)
- Characteristic code: Resistance Value (1000Ω): 1001 (as required for Variants 01 to 21) Array Reference: 1229 (as required for Variants 22 to 42)
- Characteristic code: Absolute Resistance Tolerance (±1%): F (as required)
- Characteristic code: Relative Resistance Tolerance (±0.05%): W (as required)
- Characteristic code: Absolute Temperature Coefficient (±10x10⁻⁶/°C): 1

1.4.1.1 Characteristics and/or Ratings Codes

Characteristics and/or ratings to be codified as part of the ESCC Component Number shall be as follows:

(a) Resistance Value

For resistor arrays that are specified as having individual resistors with the same single ohmic value (Variants 01 to 21), the rated resistance value, R_n , shall be expressed by means of the following codes in accordance with ESCC Basic Specification No. 21700. The unit quantity shall be ohm (Ω):

Resistance Value (Ω)	Code
XXX	XXX0
XXX 10 ¹	XXX1
XXX 10 ²	XXX2



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Resistance Value (Ω)	Code
XXX 10 ³	XXX3
XXX 10 ⁴	XXX4

(b) Array Reference

Resistor arrays that are specified as having individual resistors with 2 or more different ohmic values (Variants 22 to 42) shall each be assigned with a unique 4 digit array reference code by the Manufacturer, to represent the specific array configuration. Each array reference code shall be held by the Manufacturer under configuration control and shall contain the following information:

- The 4 digit array reference code.
- The rated resistance value, R_n , and location for each resistor in the array.
- (c) Absolute and Relative Resistance Tolerance expressed by the following codes in accordance with ESCC Basic Specification No. 21700:

Tolerance (± %)	Code Letter
0.05	W
0.1	В
0.5	D
1	F

(d) Absolute Temperature Coefficient expressed by the following code in accordance with ESCC Basic Specification:

Temperature Coefficient (± 10 ⁻⁶ /°C)	Code
10	1

1.4.2 Component Type Variants and Range of Components

The component type variants and range of components applicable to this specification are as follows:

Variant Number	Style (Note 1)	Same (S) or Different (D) Ohmic Array		erent Resistors per R _n Dhmic Array (Notes 3, 4)		Tolerance (± %)		Temperature Coefficient TC (± 10 ^{-6/o} C)		Terminal Material and	Weight max (g)
		Values (Note 2)		Min (Ω)	Max (MΩ)	Absolute	Relative	Absolute	Relative (Note 5)	Finish	
01	PRA100	S	2	100	0.2	0.1, 0.5, 1	0.05, 0.1	10	5, 3	E4	0.006
02	PRA100	S	3	100	0.2	0.1, 0.5, 1	0.05, 0.1	10	5, 3	E4	0.009
03	PRA100	S	4	100	0.2	0.1, 0.5, 1	0.05, 0.1	10	5, 3	E4	0.012
04	PRA100	S	5	100	0.2	0.1, 0.5, 1	0.05, 0.1	10	5, 3	E4	0.015
05	PRA100	S	6	100	0.2	0.1, 0.5, 1	0.05, 0.1	10	5, 3	E4	0.018
06	PRA100	S	7	100	0.2	0.1, 0.5, 1	0.05, 0.1	10	5, 3	E4	0.021
07	PRA100	S	8	100	0.2	0.1, 0.5, 1	0.05, 0.1	10	5, 3	E4	0.024
08	PRA135	S	2	100	0.25	0.1, 0.5, 1	0.05, 0.1	10	5, 3	E4	0.008
09	PRA135	S	3	100	0.25	0.1, 0.5, 1	0.05, 0.1	10	5, 3	E4	0.012
10	PRA135	S	4	100	0.25	0.1, 0.5, 1	0.05, 0.1	10	5, 3	E4	0.016



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Variant Number	Style (Note 1)	ote 1) Different Resistors per (D) Ohmic Array		F	Resistance Range R _n (Notes 3, 4)		Tolerance (± %)		erature ient TC ^{-6/º} C)	Terminal Material and	Weight max (g)
		Values (Note 2)		Min (Ω)	Max (MΩ)	Absolute	Relative	Absolute	Relative (Note 5)	Finish	
11	PRA135	S	5	100	0.25	0.1, 0.5, 1	0.05, 0.1	10	5, 3	E4	0.02
12	PRA135	S	6	100	0.25	0.1, 0.5, 1	0.05, 0.1	10	5, 3	E4	0.024
13	PRA135	S	7	100	0.25	0.1, 0.5, 1	0.05, 0.1	10	5, 3	E4	0.028
14	PRA135	S	8	100	0.25	0.1, 0.5, 1	0.05, 0.1	10	5, 3	E4	0.032
15	PRA182	S	2	100	1	0.1, 0.5, 1	0.05, 0.1	10	5, 3	E4	0.02
16	PRA182	S	3	100	1	0.1, 0.5, 1	0.05, 0.1	10	5, 3	E4	0.03
17	PRA182	S	4	100	1	0.1, 0.5, 1	0.05, 0.1	10	5, 3	E4	0.04
18	PRA182	S	5	100	1	0.1, 0.5, 1	0.05, 0.1	10	5, 3	E4	0.05
19	PRA182	S	6	100	1	0.1, 0.5, 1	0.05, 0.1	10	5, 3	E4	0.06
20	PRA182	S	7	100	1	0.1, 0.5, 1	0.05, 0.1	10	5, 3	E4	0.07
21	PRA182	S	8	100	1	0.1, 0.5, 1	0.05, 0.1	10	5, 3	E4	0.08
22	PRA100	D	2	100	0.2	0.1, 0.5, 1	0.05, 0.1	10	5, 3	E4	0.006
23	PRA100	D	3	100	0.2	0.1, 0.5, 1	0.05, 0.1	10	5, 3	E4	0.009
24	PRA100	D	4	100	0.2	0.1, 0.5, 1	0.05, 0.1	10	5, 3	E4	0.012
25	PRA100	D	5	100	0.2	0.1, 0.5, 1	0.05, 0.1	10	5, 3	E4	0.015
26	PRA100	D	6	100	0.2	0.1, 0.5, 1	0.05, 0.1	10	5, 3	E4	0.018
27	PRA100	D	7	100	0.2	0.1, 0.5, 1	0.05, 0.1	10	5, 3	E4	0.021
28	PRA100	D	8	100	0.2	0.1, 0.5, 1	0.05, 0.1	10	5, 3	E4	0.024
29	PRA135	D	2	100	0.25	0.1, 0.5, 1	0.05, 0.1	10	5, 3	E4	0.008
30	PRA135	D	3	100	0.25	0.1, 0.5, 1	0.05, 0.1	10	5, 3	E4	0.012
31	PRA135	D	4	100	0.25	0.1, 0.5, 1	0.05, 0.1	10	5, 3	E4	0.016
32	PRA135	D	5	100	0.25	0.1, 0.5, 1	0.05, 0.1	10	5, 3	E4	0.02
33	PRA135	D	6	100	0.25	0.1, 0.5, 1	0.05, 0.1	10	5, 3	E4	0.024
34	PRA135	D	7	100	0.25	0.1, 0.5, 1	0.05, 0.1	10	5, 3	E4	0.028
35	PRA135	D	8	100	0.25	0.1, 0.5, 1	0.05, 0.1	10	5, 3	E4	0.032
36	PRA182	D	2	100	1	0.1, 0.5, 1	0.05, 0.1	10	5, 3	E4	0.02
37	PRA182	D	3	100	1	0.1, 0.5, 1	0.05, 0.1	10	5, 3	E4	0.03
38	PRA182	D	4	100	1	0.1, 0.5, 1	0.05, 0.1	10	5, 3	E4	0.04
39	PRA182	D	5	100	1	0.1, 0.5, 1	0.05, 0.1	10	5, 3	E4	0.05
40	PRA182	D	6	100	1	0.1, 0.5, 1	0.05, 0.1	10	5, 3	E4	0.06
41	PRA182	D	7	100	1	0.1, 0.5, 1	0.05, 0.1	10	5, 3	E4	0.07
42	PRA182	D	8	100	1	0.1, 0.5, 1	0.05, 0.1	10	5, 3	E4	0.08

NOTES:

1. See Physical Dimensions.

2. For S types (Variants 01 to 21) all individual resistors in the resistor array have the same ohmic value, R_n .

For D types (Variants 22 to 42) the resistor array has individual resistors with 2 or more different



ohmic values.

3. The critical resistance for each style is as follows:

Variant Number	Style	Critical Resistance (kΩ)
01 to 07, 22 to 28	PRA100	12.25
08 to 14, 29 to 35	PRA135	56.25
15 to 21, 36 to 42	PRA182	100

- 4. Any value(s) in the resistance range to 3 significant figures can be selected.
- 5. $\pm 5 \times 10^{-6/\circ}$ C: if one or more resistors of the array is in the range: $100\Omega \le R_n \le 250\Omega$. $\pm 3 \times 10^{-6/\circ}$ C: if all resistors of the array are: $R_n > 250\Omega$.

1.5 MAXIMUM RATINGS

The maximum ratings shall not be exceeded at any time during use or storage. Maximum ratings shall only be exceeded during testing to the extent specified in this specification and when stipulated in Test Methods and Procedures of the ESCC Generic Specification.

Characteristics	Variant Number	Style	Symbols	Limits	Units	Remarks
Rated Dissipation	All	All	P _n	100	mW/resistor	Note 1
Limiting Element Voltage	01 to 07, 22 to 28 08 to 14, 29 to 35 15 to 21, 36 to 42	PRA100 PRA135 PRA182	UL	35 75 100	V	Per resistor
Rated Voltage	All	All	U _R	$\sqrt{(P_n x R_n)}$	V	Per resistor Note 2
Isolation Voltage	01 to 07, 22 to 28 08 to 14, 29 to 35 15 to 21, 36 to 42	PRA100 PRA135 PRA182	U _i	70 150 200	Vrms	Per resistor
Operating Temperature Range	All	All	T _{op}	-55 to +155	°C	T _{amb}
Storage Temperature Range	All	All	T _{stg}	-55 to +155	°C	-
Soldering Temperature	All	All	T _{sol}	+260	°C	Note 3

NOTES:

- 1. At $T_{amb} \le +70^{\circ}$ C. For $T_{amb} > +70^{\circ}$ C derate linearly to 0W at $T_{amb} = +155^{\circ}$ C.
- 2. Shall never exceed Limiting Element Voltage. R_n=Rated Resistance.
- 3. Duration 10 seconds maximum.

1.6 HANDLING PRECAUTIONS

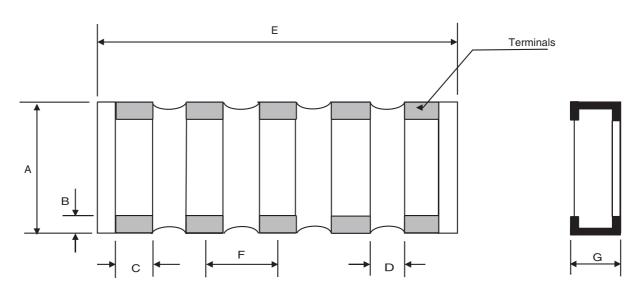
These devices are susceptible to damage by electrostatic discharge. Therefore, suitable precautions shall be employed for protection during all phases of manufacture, testing, packaging, shipment and any handling.



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These components are categorised as Class 2 per ESCC Basic Specification No. 23800 with a Minimum Critical Path Failure Voltage of 2500 Volts.

1.7 PHYSICAL DIMENSIONS AND TERMINAL IDENTIFICATION



Variant	Style		Dimensions (mm)											
Number		ŀ	4	E	3	C	;	[)	C	G	F	=	E
		Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	
01 to 07, 22 to 28	PRA100	1.5	1.8	0.2	0.6	0.5	0.8	0.2	0.3	0.38	0.58	0.95	1.05	Note 1
08 to 14, 29 to 35	PRA135	1.75	2.05	0.2	0.6	0.9	1.2	0.2	0.3	0.38	0.58	1.3	1.4	Note 1
15 to 21, 36 to 42	PRA182	2.9	3.2	0.2	0.6	1.15	1.45	0.2	0.3	0.38	0.58	1.77	1.87	Note 1

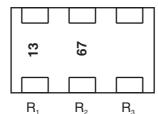
NOTES:

1. E=(NxF)±0.3mm, where N= number of resistors per array (N=2 to 8).

2. Terminal identification shall be by means of the location of the marking. Due to the size of the component only the 4 digit resistance value code or array reference code, as applicable (see The ESCC Component Number), shall be marked on the component.

For symmetrical marking using reversible figures such as 0, 6 or 9, the first resistor of the array, R_1 , shall be identified by a dot.

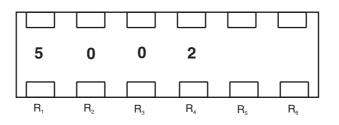
For arrays with 2 or 3 resistors, the marking shall be located adjacent to the first 2 resistors of the array. The first resistor, R_1 , of the array is the upper resistor whilst reading the marking, as follows:



For arrays with 4 to 8 resistors, the marking shall be located adjacent to the first 4 resistors of the

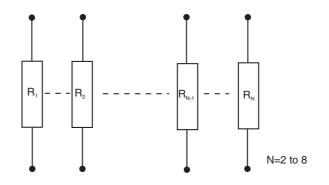


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array. The first resistor, R_1 , of the array is on the left hand end of the array whilst reading the marking, as follows:

1.8 <u>FUNCTIONAL DIAGRAM</u>



1.9 <u>MATERIALS AND FINISHES</u>

1.9.1 <u>Body</u>

Each resistive element deposited on the alumina substrate shall be covered with a suitable coating.

1.9.2 <u>Terminations</u>

The terminal material and finish shall be as specified in Component Type Variants and Range of Components in accordance with the requirements of ESCC Basic Specification No. 23500.

2. <u>REQUIREMENTS</u>

2.1 <u>GENERAL</u>

The complete requirements for procurement of the components specified herein are as stated in this specification and the ESCC Generic Specification. Permitted deviations from the Generic Specification, applicable to this specification only, are listed below.

Permitted deviations from the Generic Specification and this Detail Specification, formally agreed with specific Manufacturers on the basis that the alternative requirements are equivalent to the ESCC requirement and do not affect the component's reliability, are listed in the appendices attached to this specification.



2.1.1 <u>Deviations from the Generic Specification</u>

2.1.1.1 Deviations from Screening Tests (Chart F3)

(a) Para. 8.2, Non-Linearity: Voltage on each resistor of the array = $\sqrt{(P_n \times R_{min})}$ or 2U_L, whichever is less (R_{min} is the lowest ohmic value of the array).

2.1.1.2 Deviations from Qualification and Periodic Tests (Chart F4)

- (a) Para. 8.9, Vibration: Not applicable.
- (b) Para. 8.10, Climatic Sequence: Voltage applied during the Low Air Pressure test: as per Burn-in herein.

2.2 MARKING

The marking of all components delivered to this specification shall be in accordance with the requirements of ESCC Basic Specification No. 21700. When the component is too small to accommodate all of the marking specified, as much as space permits shall be marked and the marking information, in full, shall accompany each component in its primary package.

The information to be marked and the order of precedence, shall be as follows:

- (a) Rated Resistance (for Variants 01 to 21); Terminal identification and array reference code (for Variants 22 to 42) (see Physical Dimensions and Terminal Identification))
- (b) The ESCC qualified components symbol (for ESCC qualified components only).
- (c) The ESCC Component Number.
- (d) Traceability information.

2.3 OVERLOAD

The test conditions for Overload, tested as specified in the ESCC Generic Specification, shall be as follows:

Voltage on each resistor of the array:	$\sqrt{(6.25P_n x R_{min})}$ or 2U _L , whichever is less (R _{min} is the
	lowest ohmic value of the array).
Duration:	2s minimum.

2.4 ROBUSTNESS OF TERMINATIONS - SUBSTRATE BENDING TEST

The test conditions for the Substrate bending Test, tested as specified in the ESCC Generic Specification, shall be as follows:

Number of bends:	10.
Deflection:	2mm (all Variants)
Duration:	5±1s
Orientation:	Same orientation as for a single resistor



2.5 RESISTANCE TO SOLDERING HEAT

The test conditions for Resistance to Soldering Heat, tested as specified in the ESCC Generic Specification, shall be as follows:

Temperature:	260°C
Duration:	10(+0-1)s

2.6 ELECTRICAL MEASUREMENTS AT ROOM, HIGH AND LOW TEMPERATURES

2.6.1 <u>Room Temperature Electrical Measurements</u>

The measurements shall be performed at T_{amb} =+22 ±3°C.

Characteristics			C 4001 Test Tolerance	Lin	Units	
		Method and Conditions	(± %)	Min	Max	
Resistance	R _A	Para. 8.3.1.1	0.1	0.999 R _n	1.001 R _n	Ω
		Note 1	0.5	0.995 R _n	1.005 R _n	
			1	0.99 R _n	1.01 R _n	
Relative Tolerance	ΔT_R	Para. 8.3.1.1 Note 2	0.05 0.1	-0.05 -0.1	+0.05 +0.1	%
Insulation Resistance	R _I	Para. 8.3.1.2 V=100V Note 3	All	1000	-	MΩ

NOTES:

1. The measurements shall be performed on all the individual resistors of the array.

2.

$$\Delta T_{R} = Max \left[\frac{R_{A} - R_{n}}{R_{n}} \right] - Min \left[\frac{R_{A} - R_{n}}{R_{n}} \right]$$

The calculations shall be performed between all the resistor pairs of the array.

3. Guaranteed but not tested during Screening Tests.

2.6.2 <u>High and Low Temperatures Electrical Measurements</u>

Characteristics	Symbols	ESCC 4001 Test Method and Conditions		Limits		Unit	
				Min	Max		
Resistance Change be- tween -55 $(+3-0)^{\circ}$ C and +22 ± 3°C	$\Delta R_A/R_A$	Para. 8.3.1.1	Notes 1 and 2	-0.08	+0.08	%	
Resistance Change be- tween +155 $(+0 -3)^{\circ}$ C and +22 ± 3°C	$\Delta R_A/R_A$	Para. 8.3.1.1	Notes 1 and 2	-0.136	+0.136	%	



Characteristics	Symbols	ESCC 4001 Test Method and Conditions		Lin	Unit	
				Min	Max	
Relative Temperature	∆TC _R	Para. 8.3.1.1	Notes 2 and 3	-3	+3	10 ⁻⁶ /ºC
Coefficient -55 (+3 -0) ^o C		Para. 8.3.1.1	Notes 2 and 3	-5	+5	
Relative Temperature	∆TC _R	Para. 8.3.1.1	Notes 2 and 3	-3	+3	10 ⁻⁶ /ºC
Coefficient -155 (+3 -0) ^o C		Para. 8.3.1.1	Notes 2 and 3	-5	+5	

NOTES:

- 1. The measurements shall be performed on all the individual resistors of the array.
- 2. The measurements shall be performed on a sample of 5 components selected from the total production lot. The components shall be mounted as specified in the ESCC Generic Specification.
- 3. See Component Type Variants and Range of Components Note 5.

$$\Delta TC_{R} = Max \left[\frac{R_{A(T^{\circ})} - R_{A(T)}}{R_{A(T^{\circ})}} \bullet \frac{1}{(T^{\circ} - T)} \right] - Min \left[\frac{R_{A(T^{\circ})} - R_{A(T)}}{R_{A(T^{\circ})}} \bullet \frac{1}{(T^{\circ} - T)} \right]$$

The calculations are done between all the resistor pairs of the array.

(T^o) is the reference temperature of the test method (+22 \pm 3°C).

(T) is the high $(+155 (+0 -3)^{\circ}C \text{ or the low } (-55 (+3 -0)^{\circ}C) \text{ testing temperature.}$

7 INTERMEDIATE AND END-POINT ELECTRICAL MEASUREMENTS

The components shall be mounted as specified in the ESCC Generic Specification.

Unless otherwise specified, the measurements shall be performed at T_{amb} =+22 ±3°C.

Unless otherwise specified the test methods and test conditions shall be as per the corresponding test defined in Room Temperature Electrical Measurements.

Test Reference per			Lin	nits	Units
ESCC No. 4001			Min	Max	
Rapid Change of Temperature					
Initial Measurement	Resistance	R _A	Record	Values	
	Relative Tolerance	ΔT_R	See Pa	ra. 2.6.1	
Final Measurement	Change in Resistance	$\Delta R_A/R_A$	±(0.05 + % 0.05Ωx100/R _n)		%
	Relative Tolerance	ΔT_R	See Pa	ra. 2.6.1	
Robustness of Terminations					
Initial Measurement	Resistance	R _A	Record	Values	
	Relative Tolerance	ΔT_R	See Para. 2.6.1		
Final Measurement	Change in Resistance	$\Delta R_A/R_A$	±(0.05 + % 0.05Ωx100/R _n)		%

2.7



Test Reference per	Characteristics	Symbols	Lin	nits	Units
ESCC No. 4001			Min	Max	
	Relative Tolerance	ΔT_R	See Pai	ra. 2.6.1	
Resistance to Soldering Heat					
Initial Measurement	Resistance	R _A	Record	Values	
	Relative Tolerance	ΔT_R	See Pai	ra. 2.6.1	
Final Measurement	Change in Resistance	$\Delta R_A/R_A$	· ·	05 + 100/R _n)	%
	Relative Tolerance	ΔT_R	See Pai	ra. 2.6.1	
Solderability					
Initial Measurement	Resistance	R _A	Record	Values	
	Relative Tolerance	ΔT_R	See Pai	ra. 2.6.1	
Final Measurement	Change in Resistance	$\Delta R_A/R_A$	· ·	05 + 100/R _n)	%
	Relative Tolerance	ΔT_R	See Pai	ra. 2.6.1	
Climatic Sequence					
Initial Measurements (Procedure 1)	Resistance (after drying)	R _A	Record	Values	
	Relative Tolerance	ΔT_R	See Para. 2.6.1		
Final Measurements	Relative Tolerance	ΔT_R	See Para. 2.6.1		
	Change in Resistance	$\Delta R_A/R_A$	±(0.1 + 0.05Ωx100/R _n)		%
	Insulation Resistance (V _T =100V)	R _I	1000	-	MΩ
Operating Life					
Initial Measurement (0 hour)	Resistance	R _A	Record	Values	
	Relative Tolerance	ΔT_R	See Pai	ra. 2.6.1	
Intermediate Measurements (1000 hours)	Relative Tolerance	ΔT _R	See Para. 2.6.1		
	Change in Resistance	$\Delta R_A/R_A$	±(0.1 + 0.05Ωx100/R _n)		%
Final Measurements	Relative Tolerance	ΔT_R	See Para. 2.6.1		
(2000 hours)	Change in Resistance	$\Delta R_A/R_A$		15 + 100/R _n)	%
	Insulation Resistance (V _T =100V)	R _I	1000	-	MΩ



2.8 **BURN-IN CONDITIONS**

Characteristics	Symbols	Test Conditions	Units
Ambient Temperature	T _{amb}	+70 ±5	°C
Test Voltage Variants 01 to 21 Variants 22 to 42	V _T	$\begin{array}{l} \sqrt[]{(P_n \ x \ R_n)} \ or \ U_L \\ \text{whichever is less} \\ \sqrt[]{(P_n \ x \ R_{min})} \ or \ U_L \\ \text{whichever is less} \end{array}$	V

NOTES:

- V_T is applied to each individual resistor. R_{min} is the lowest ohmic value of the array.
 After Burn-in, the components shall be removed from the chamber and allowed to cool under normal atmospheric conditions for a minimum of 4 hours.

OPERATING LIFE CONDITIONS 2.9

The conditions shall be as specified for Burn-in.



APPENDIX A

AGREED DEVIATIONS FOR VISHAY SFERNICE (F)

Items Affected	Description of Deviations
Deviations from Generic Specification:	
Screening Tests (Chart F3)	Para. 8.2, Non-Linearity: Not applicable.